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Understanding [Embedded - Microprocessors](#)

Embedded microprocessors are specialized computing chips designed to perform specific tasks within an embedded system. Unlike general-purpose microprocessors found in personal computers, embedded microprocessors are tailored for dedicated functions within larger systems, offering optimized performance, efficiency, and reliability. These microprocessors are integral to the operation of countless electronic devices, providing the computational power necessary for controlling processes, handling data, and managing communications.

Applications of [Embedded - Microprocessors](#)

Embedded microprocessors are utilized across a broad spectrum of applications, making them indispensable in

Details	
Product Status	Obsolete
Core Processor	PowerPC e500
Number of Cores/Bus Width	1 Core, 32-Bit
Speed	1.333GHz
Co-Processors/DSP	Signal Processing; SPE, Security; SEC
RAM Controllers	DDR, DDR2, SDRAM
Graphics Acceleration	No
Display & Interface Controllers	-
Ethernet	10/100/1000Mbps (4)
SATA	-
USB	-
Voltage - I/O	1.8V, 2.5V, 3.3V
Operating Temperature	-40°C ~ 105°C (TA)
Security Features	Cryptography, Random Number Generator
Package / Case	783-BBGA, FCBGA
Supplier Device Package	783-FCPBGA (29x29)
Purchase URL	https://www.e-xfl.com/product-detail/nxp-semiconductors/mpc8548ecpxaujd

- Dedicated single data rate SDRAM controller
- Parity support
- Default boot ROM chip select with configurable bus width (8, 16, or 32 bits)
- Four enhanced three-speed Ethernet controllers (eTSECs)
 - Three-speed support (10/100/1000 Mbps)
 - Four controllers designed to comply with IEEE Std. 802.3[®], 802.3u, 802.3x, 802.3z, 802.3ac, and 802.3ab
 - Support for various Ethernet physical interfaces:
 - 1000 Mbps full-duplex IEEE 802.3 GMII, IEEE 802.3z TBI, RTBI, and RGMII
 - 10/100 Mbps full and half-duplex IEEE 802.3 MII, IEEE 802.3 RGMII, and RMII
 - Flexible configuration for multiple PHY interface configurations. See [Section 8.1, “Enhanced Three-Speed Ethernet Controller \(eTSEC\) \(10/100/1Gb Mbps\)—GMII/MII/TBI/RGMII/RTBI/RMII Electrical Characteristics,”](#) for more information.
 - TCP/IP acceleration and QoS features available
 - IP v4 and IP v6 header recognition on receive
 - IP v4 header checksum verification and generation
 - TCP and UDP checksum verification and generation
 - Per-packet configurable acceleration
 - Recognition of VLAN, stacked (queue in queue) VLAN, IEEE Std 802.2[™], PPPoE session, MPLS stacks, and ESP/AH IP-security headers
 - Supported in all FIFO modes
 - Quality of service support:
 - Transmission from up to eight physical queues
 - Reception to up to eight physical queues
 - Full- and half-duplex Ethernet support (1000 Mbps supports only full duplex):
 - IEEE 802.3 full-duplex flow control (automatic PAUSE frame generation or software-programmed PAUSE frame generation and recognition)
 - Programmable maximum frame length supports jumbo frames (up to 9.6 Kbytes) and IEEE Std. 802.1[™] virtual local area network (VLAN) tags and priority
 - VLAN insertion and deletion
 - Per-frame VLAN control word or default VLAN for each eTSEC
 - Extracted VLAN control word passed to software separately
 - Retransmission following a collision
 - CRC generation and verification of inbound/outbound frames
 - Programmable Ethernet preamble insertion and extraction of up to 7 bytes
 - MAC address recognition:
 - Exact match on primary and virtual 48-bit unicast addresses

2 Electrical Characteristics

This section provides the AC and DC electrical specifications and thermal characteristics for the device. This device is currently targeted to these specifications. Some of these specifications are independent of the I/O cell, but are included for a more complete reference. These are not purely I/O buffer design specifications.

2.1 Overall DC Electrical Characteristics

This section covers the ratings, conditions, and other characteristics.

2.1.1 Absolute Maximum Ratings

The following table provides the absolute maximum ratings.

Table 1. Absolute Maximum Ratings ¹

Characteristic		Symbol	Max Value	Unit	Notes
Core supply voltage		V_{DD}	-0.3 to 1.21	V	—
PLL supply voltage		AV_{DD}	-0.3 to 1.21	V	—
Core power supply for SerDes transceivers		SV_{DD}	-0.3 to 1.21	V	—
Pad power supply for SerDes transceivers		XV_{DD}	-0.3 to 1.21	V	—
DDR and DDR2 DRAM I/O voltage		GV_{DD}	-0.3 to 2.75 -0.3 to 1.98	V	2
Three-speed Ethernet I/O voltage		LV_{DD} (for eTSEC1 and eTSEC2)	-0.3 to 3.63 -0.3 to 2.75	V	3
		TV_{DD} (for eTSEC3 and eTSEC4)	-0.3 to 3.63 -0.3 to 2.75		
PCI/PCI-X, DUART, system control and power management, I ² C, Ethernet MII management, and JTAG I/O voltage		OV_{DD}	-0.3 to 3.63	V	—
Local bus I/O voltage		BV_{DD}	-0.3 to 3.63 -0.3 to 2.75	V	—
Input voltage	DDR/DDR2 DRAM signals	MV_{IN}	-0.3 to ($GV_{DD} + 0.3$)	V	4
	DDR/DDR2 DRAM reference	MV_{REF}	-0.3 to ($GV_{DD}/2 + 0.3$)	V	—
	Three-speed Ethernet I/O signals	LV_{IN} TV_{IN}	-0.3 to ($LV_{DD} + 0.3$) -0.3 to ($TV_{DD} + 0.3$)	V	4
	Local bus signals	BV_{IN}	-0.3 to ($BV_{DD} + 0.3$)	—	—
	DUART, SYSCLK, system control and power management, I ² C, Ethernet MII management, and JTAG signals	OV_{IN}	-0.3 to ($OV_{DD} + 0.3$)	V	4
	PCI/PCI-X	OV_{IN}	-0.3 to ($OV_{DD} + 0.3$)	V	4

7 DUART

This section describes the DC and AC electrical specifications for the DUART interface of the device.

7.1 DUART DC Electrical Characteristics

This table provides the DC electrical characteristics for the DUART interface.

Table 20. DUART DC Electrical Characteristics

Parameter	Symbol	Min	Max	Unit
High-level input voltage	V_{IH}	2	$OV_{DD} + 0.3$	V
Low-level input voltage	V_{IL}	-0.3	0.8	V
Input current ($V_{IN}^1 = 0$ V or $V_{IN} = V_{DD}$)	I_{IN}	—	± 5	μ A
High-level output voltage ($OV_{DD} = \text{min}$, $I_{OH} = -2$ mA)	V_{OH}	2.4	—	V
Low-level output voltage ($OV_{DD} = \text{min}$, $I_{OL} = 2$ mA)	V_{OL}	—	0.4	V

Note:

- Note that the symbol V_{IN} , in this case, represents the OV_{IN} symbol referenced in [Table 1](#) and [Table 2](#).

7.2 DUART AC Electrical Specifications

This table provides the AC timing parameters for the DUART interface.

Table 21. DUART AC Timing Specifications

Parameter	Value	Unit	Notes
Minimum baud rate	$f_{CCB}/1,048,576$	baud	1, 2
Maximum baud rate	$f_{CCB}/16$	baud	1, 2, 3
Oversample rate	16	—	1, 4

Notes:

- Guaranteed by design.
- f_{CCB} refers to the internal platform clock.
- Actual attainable baud rate is limited by the latency of interrupt processing.
- The middle of a start bit is detected as the 8th sampled 0 after the 1-to-0 transition of the start bit. Subsequent bit values are sampled each 16th sample.

10.2 Local Bus AC Electrical Specifications

This table describes the timing parameters of the local bus interface at $BV_{DD} = 3.3$ V. For information about the frequency range of local bus, see [Section 20.1, “Clock Ranges.”](#)

Table 40. Local Bus Timing Parameters ($BV_{DD} = 3.3$ V)—PLL Enabled

Parameter	Symbol ¹	Min	Max	Unit	Notes
Local bus cycle time	t_{LBK}	7.5	12	ns	2
Local bus duty cycle	t_{LBKH}/t_{LBK}	43	57	%	—
LCLK[n] skew to LCLK[m] or LSYNC_OUT	$t_{LBKSKEW}$	—	150	ps	7, 8
Input setup to local bus clock (except $\overline{LGTA}/LUPWAIT$)	$t_{LBIVKH1}$	1.8	—	ns	3, 4
$\overline{LGTA}/LUPWAIT$ input setup to local bus clock	$t_{LBIVKH2}$	1.7	—	ns	3, 4
Input hold from local bus clock (except $\overline{LGTA}/LUPWAIT$)	$t_{LBIXKH1}$	1.0	—	ns	3, 4
$\overline{LGTA}/LUPWAIT$ input hold from local bus clock	$t_{LBIXKH2}$	1.0	—	ns	3, 4
LALE output transition to LAD/LDP output transition (LATCH hold time)	t_{LBOTOT}	1.5	—	ns	6
Local bus clock to output valid (except LAD/LDP and LALE)	$t_{LBKHOV1}$	—	2.0	ns	—
Local bus clock to data valid for LAD/LDP	$t_{LBKHOV2}$	—	2.2	ns	3
Local bus clock to address valid for LAD	$t_{LBKHOV3}$	—	2.3	ns	3
Local bus clock to LALE assertion	$t_{LBKHOV4}$	—	2.3	ns	3
Output hold from local bus clock (except LAD/LDP and LALE)	$t_{LBKHOX1}$	0.7	—	ns	3
Output hold from local bus clock for LAD/LDP	$t_{LBKHOX2}$	0.7	—	ns	3
Local bus clock to output high Impedance (except LAD/LDP and LALE)	$t_{LBKHOZ1}$	—	2.5	ns	5
Local bus clock to output high impedance for LAD/LDP	$t_{LBKHOZ2}$	—	2.5	ns	5

Notes:

- The symbols used for timing specifications follow the pattern of $t_{(\text{first two letters of functional block})(\text{signal})(\text{state})(\text{reference})(\text{state})}$ for inputs and $t_{(\text{first two letters of functional block})(\text{reference})(\text{state})(\text{signal})(\text{state})}$ for outputs. For example, $t_{LBIXKH1}$ symbolizes local bus timing (LB) for the input (I) to go invalid (X) with respect to the time the t_{LBK} clock reference (K) goes high (H), in this case for clock one (1). Also, t_{LBKHOX} symbolizes local bus timing (LB) for the t_{LBK} clock reference (K) to go high (H), with respect to the output (O) going invalid (X) or output hold time.
- All timings are in reference to LSYNC_IN for PLL enabled and internal local bus clock for PLL bypass mode.
- All signals are measured from $BV_{DD}/2$ of the rising edge of LSYNC_IN for PLL enabled or internal local bus clock for PLL bypass mode to $0.4 \times BV_{DD}$ of the signal in question for 3.3-V signaling levels.
- Input timings are measured at the pin.
- For purposes of active/float timing measurements, the Hi-Z or off state is defined to be when the total current delivered through the component pin is less than or equal to the leakage current specification.
- t_{LBOTOT} is a measurement of the minimum time between the negation of LALE and any change in LAD. t_{LBOTOT} is programmed with the LBCR[AHD] parameter.
- Maximum possible clock skew between a clock LCLK[m] and a relative clock LCLK[n]. Skew measured between complementary signals at $BV_{DD}/2$.
- Guaranteed by design.

Figure 34 shows the AC timing diagram for the I²C bus.

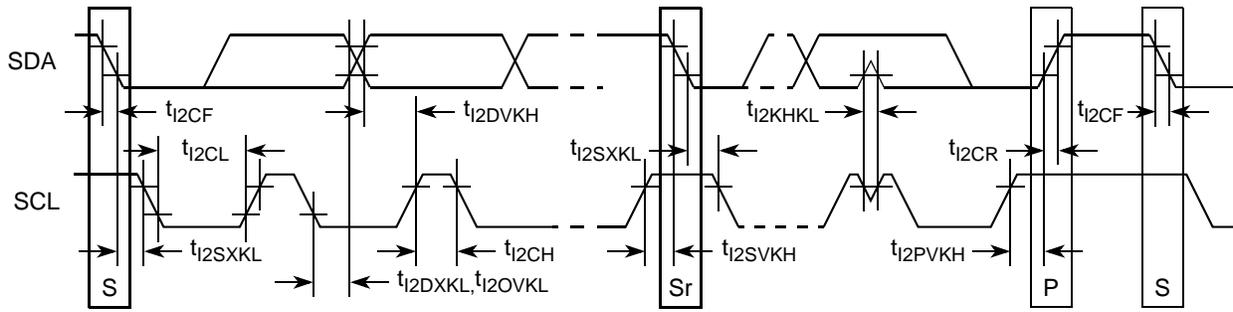


Figure 34. I²C Bus AC Timing Diagram

of a balanced interchange circuit and ground. In this example, for SerDes output, $V_{cm_out} = V_{SD_TX} + V_{\overline{SD_TX}} = (A + B)/2$, which is the arithmetic mean of the two complimentary output voltages within a differential pair. In a system, the common mode voltage may often differ from one component's output to the other's input. Sometimes, it may be even different between the receiver input and driver output circuits within the same component. It is also referred to as the DC offset.

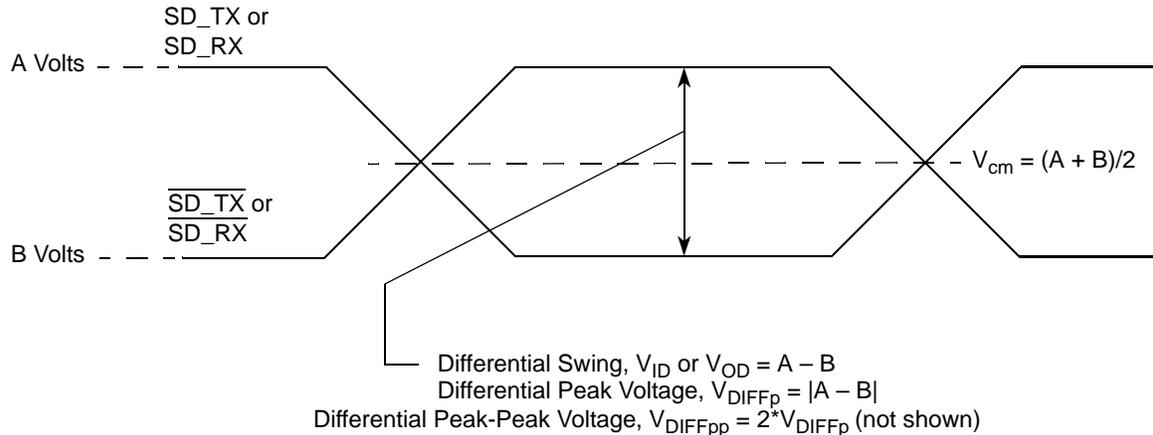


Figure 38. Differential Voltage Definitions for Transmitter or Receiver

To illustrate these definitions using real values, consider the case of a CML (current mode logic) transmitter that has a common mode voltage of 2.25 V and each of its outputs, TD and \overline{TD} , has a swing that goes between 2.5 and 2.0 V. Using these values, the peak-to-peak voltage swing of each signal (TD or \overline{TD}) is 500 mVp-p, which is referred as the single-ended swing for each signal. In this example, since the differential signaling environment is fully symmetrical, the transmitter output's differential swing (V_{OD}) has the same amplitude as each signal's single-ended swing. The differential output signal ranges between 500 and -500 mV, in other words, V_{OD} is 500 mV in one phase and -500 mV in the other phase. The peak differential voltage (V_{DIFFp}) is 500 mV. The peak-to-peak differential voltage ($V_{DIFFp-p}$) is 1000 mVp-p.

16.2 SerDes Reference Clocks

The SerDes reference clock inputs are applied to an internal PLL whose output creates the clock used by the corresponding SerDes lanes. The SerDes reference clocks inputs are SD_REF_CLK and $\overline{SD_REF_CLK}$ for PCI Express and serial RapidIO.

The following sections describe the SerDes reference clock requirements and some application information.

16.2.1 SerDes Reference Clock Receiver Characteristics

Figure 39 shows a receiver reference diagram of the SerDes reference clocks.

- The supply voltage requirements for XV_{DD_SRDS2} are specified in Table 1 and Table 2.
- SerDes Reference clock receiver reference circuit structure:

Table 57. Differential Receiver (RX) Input Specifications (continued)

Symbol	Parameter	Min	Nom	Max	Unit	Comments
$L_{TX-SKEW}$	Total Skew	—	—	20	ns	Skew across all lanes on a Link. This includes variation in the length of SKP ordered set (for example, COM and one to five symbols) at the RX as well as any delay differences arising from the interconnect itself.

Notes:

1. No test load is necessarily associated with this value.
2. Specified at the measurement point and measured over any 250 consecutive UIs. The test load in [Figure 50](#) must be used as the RX device when taking measurements (also see the receiver compliance eye diagram shown in [Figure 49](#)). If the clocks to the RX and TX are not derived from the same reference clock, the TX UI recovered from 3500 consecutive UI must be used as a reference for the eye diagram.
3. A $T_{RX-EYE} = 0.40$ UI provides for a total sum of 0.60 UI deterministic and random jitter budget for the transmitter and interconnect collected any 250 consecutive UIs. The $T_{RX-EYE-MEDIAN-to-MAX-JITTER}$ specification ensures a jitter distribution in which the median and the maximum deviation from the median is less than half of the total. UI jitter budget collected over any 250 consecutive TX UIs. Note that the median is not the same as the mean. The jitter median describes the point in time where the number of jitter points on either side is approximately equal as opposed to the averaged time value. If the clocks to the RX and TX are not derived from the same reference clock, the TX UI recovered from 3500 consecutive UI must be used as the reference for the eye diagram.
4. The receiver input impedance shall result in a differential return loss greater than or equal to 15 dB with the D+ line biased to 300 mV and the D– line biased to –300 mV and a common mode return loss greater than or equal to 6 dB (no bias required) over a frequency range of 50 MHz to 1.25 GHz. This input impedance requirement applies to all valid input levels. The reference impedance for return loss measurements for is 50 Ω to ground for both the D+ and D– line (that is, as measured by a vector network analyzer with 50- Ω probes—see [Figure 50](#)). Note: that the series capacitors CTX is optional for the return loss measurement.
5. Impedance during all LTSSM states. When transitioning from a fundamental reset to detect (the initial state of the LTSSM) there is a 5 ms transition time before receiver termination values must be met on all unconfigured lanes of a port.
6. The RX DC common mode Impedance that exists when no power is present or fundamental reset is asserted. This helps ensure that the receiver detect circuit does not falsely assume a receiver is powered on when it is not. This term must be measured at 300 mV above the RX ground.
7. It is recommended that the recovered TX UI is calculated using all edges in the 3500 consecutive UI interval with a fit algorithm using a minimization merit function. Least squares and median deviation fits have worked well with experimental and simulated data.

17.5 Receiver Compliance Eye Diagrams

The RX eye diagram in [Figure 49](#) is specified using the passive compliance/test measurement load (see [Figure 50](#)) in place of any real PCI Express RX component.

Note: In general, the minimum receiver eye diagram measured with the compliance/test measurement load (see [Figure 50](#)) is larger than the minimum receiver eye diagram measured over a range of systems at the input receiver of any real PCI Express component. The degraded eye diagram at the input receiver is due to traces internal to the package as well as silicon parasitic characteristics which cause the real PCI Express component to vary in impedance from the compliance/test measurement load. The input receiver eye diagram is implementation specific and is not specified. RX component designer must provide additional margin to adequately compensate for the degraded minimum receiver eye diagram (shown in [Figure 49](#)) expected at the input receiver based on some adequate combination of system simulations and the return loss measured looking into the RX package and silicon. The RX eye diagram must be aligned in time using the jitter median to locate the center of the eye diagram.

components are included in this requirement. The reference impedance for return loss measurements is 100- Ω resistive for differential return loss and 25- Ω resistive for common mode.

Table 66. Receiver AC Timing Specifications—1.25 GBaud

Characteristic	Symbol	Range		Unit	Notes
		Min	Max		
Differential input voltage	V_{IN}	200	1600	mVp-p	Measured at receiver
Deterministic jitter tolerance	J_D	0.37	—	UI p-p	Measured at receiver
Combined deterministic and random jitter tolerance	J_{DR}	0.55	—	UI p-p	Measured at receiver
Total jitter tolerance ¹	J_T	0.65	—	UI p-p	Measured at receiver
Multiple input skew	S_{MI}	—	24	ns	Skew at the receiver input between lanes of a multilane link
Bit error rate	BER	—	10^{-12}	—	—
Unit interval	UI	800	800	ps	± 100 ppm

Note:

- Total jitter is composed of three components, deterministic jitter, random jitter, and single frequency sinusoidal jitter. The sinusoidal jitter may have any amplitude and frequency in the unshaded region of [Figure 53](#). The sinusoidal jitter component is included to ensure margin for low frequency jitter, wander, noise, crosstalk, and other variable system effects.

Table 67. Receiver AC Timing Specifications—2.5 GBaud

Characteristic	Symbol	Range		Unit	Notes
		Min	Max		
Differential input voltage	V_{IN}	200	1600	mVp-p	Measured at receiver
Deterministic jitter tolerance	J_D	0.37	—	UI p-p	Measured at receiver
Combined deterministic and random jitter tolerance	J_{DR}	0.55	—	UI p-p	Measured at receiver
Total jitter tolerance ¹	J_T	0.65	—	UI p-p	Measured at receiver
Multiple input skew	S_{MI}	—	24	ns	Skew at the receiver input between lanes of a multilane link
Bit error rate	BER	—	10^{-12}	—	—
Unit interval	UI	400	400	ps	± 100 ppm

Note:

- Total jitter is composed of three components, deterministic jitter, random jitter, and single frequency sinusoidal jitter. The sinusoidal jitter may have any amplitude and frequency in the unshaded region of [Figure 53](#). The sinusoidal jitter component is included to ensure margin for low frequency jitter, wander, noise, crosstalk, and other variable system effects.

802.3ae-2002 is specified as the test pattern for use in eye pattern and jitter measurements. Annex 48B of IEEE Std. 802.3ae-2002 is recommended as a reference for additional information on jitter test methods.

18.9.1 Eye Template Measurements

For the purpose of eye template measurements, the effects of a single-pole high pass filter with a 3 dB point at (baud frequency)/1667 is applied to the jitter. The data pattern for template measurements is the continuous jitter test pattern (CJPAT) defined in Annex 48A of IEEE 802.3ae. All lanes of the LP-serial link shall be active in both the transmit and receive directions, and opposite ends of the links shall use asynchronous clocks. Four lane implementations shall use CJPAT as defined in Annex 48A. Single lane implementations shall use the CJPAT sequence specified in Annex 48A for transmission on lane 0. The amount of data represented in the eye shall be adequate to ensure that the bit error ratio is less than 10^{-12} . The eye pattern shall be measured with AC coupling and the compliance template centered at 0 V differential. The left and right edges of the template shall be aligned with the mean zero crossing points of the measured data eye. The load for this test shall be 100- Ω resistive \pm 5% differential to 2.5 GHz.

18.9.2 Jitter Test Measurements

For the purpose of jitter measurement, the effects of a single-pole high pass filter with a 3 dB point at (baud frequency)/1667 is applied to the jitter. The data pattern for jitter measurements is the Continuous Jitter test pattern (CJPAT) pattern defined in Annex 48A of IEEE 802.3ae. All lanes of the LP-serial link shall be active in both the transmit and receive directions, and opposite ends of the links shall use asynchronous clocks. Four lane implementations shall use CJPAT as defined in Annex 48A. Single lane implementations shall use the CJPAT sequence specified in Annex 48A for transmission on lane 0. Jitter shall be measured with AC coupling and at 0 V differential. Jitter measurement for the transmitter (or for calibration of a jitter tolerance setup) shall be performed with a test procedure resulting in a BER curve such as that described in Annex 48B of IEEE 802.3ae.

18.9.3 Transmit Jitter

Transmit jitter is measured at the driver output when terminated into a load of 100 Ω resistive \pm 5% differential to 2.5 GHz.

18.9.4 Jitter Tolerance

Jitter tolerance is measured at the receiver using a jitter tolerance test signal. This signal is obtained by first producing the sum of deterministic and random jitter defined in [Section 18.7, “Receiver Specifications,”](#) and then adjusting the signal amplitude until the data eye contacts the 6 points of the minimum eye opening of the receive template shown in [Figure 54](#) and [Table 69](#). Note that for this to occur, the test signal must have vertical waveform symmetry about the average value and have horizontal symmetry (including jitter) about the mean zero crossing. Eye template measurement requirements are as defined above. Random jitter is calibrated using a high pass filter with a low frequency corner at 20 MHz and a 20 dB/decade roll-off below this. The required sinusoidal jitter specified in [Section 18.7, “Receiver Specifications,”](#) is then added to the signal and the test load is replaced by the receiver being tested.

19.2 Mechanical Dimensions of the HiCTE FC-CBGA and FC-PBGA with Full Lid

The following figures show the mechanical dimensions and bottom surface nomenclature for the MPC8548E HiCTE FC-CBGA and FC-PBGA packages.

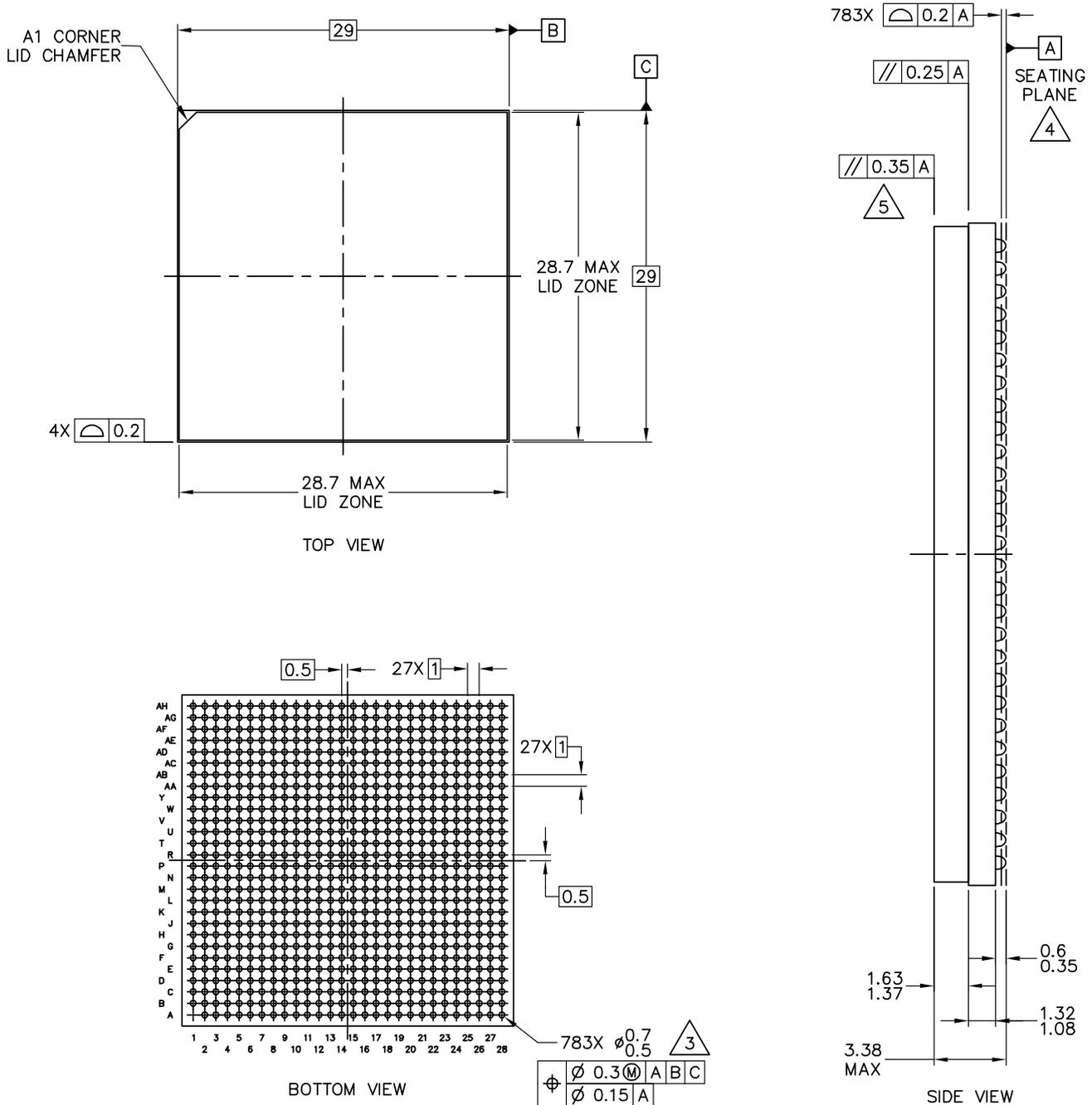


Figure 55. Mechanical Dimensions and Bottom Surface Nomenclature of the HiCTE FC-CBGA and FC-PBGA with Full Lid

Table 71. MPC8548E Pinout Listing (continued)

Signal	Package Pin Number	Pin Type	Power Supply	Notes
LSYNC_IN	F27	I	BV _{DD}	—
LSYNC_OUT	F28	O	BV _{DD}	—
DMA				
$\overline{\text{DMA_DACK}}[0:1]$	AD3, AE1	O	OV _{DD}	5, 9, 102
$\overline{\text{DMA_DREQ}}[0:1]$	AD4, AE2	I	OV _{DD}	—
$\overline{\text{DMA_DDONE}}[0:1]$	AD2, AD1	O	OV _{DD}	—
Programmable Interrupt Controller				
$\overline{\text{UDE}}$	AH16	I	OV _{DD}	—
$\overline{\text{MCP}}$	AG19	I	OV _{DD}	—
IRQ[0:7]	AG23, AF18, AE18, AF20, AG18, AF17, AH24, AE20	I	OV _{DD}	—
IRQ[8]	AF19	I	OV _{DD}	—
IRQ[9]/DMA_DREQ3	AF21	I	OV _{DD}	1
IRQ[10]/DMA_DACK3	AE19	I/O	OV _{DD}	1
IRQ[11]/DMA_DDONE3	AD20	I/O	OV _{DD}	1
$\overline{\text{IRQ_OUT}}$	AD18	O	OV _{DD}	2, 4
Ethernet Management Interface				
EC_MDC	AB9	O	OV _{DD}	5, 9
EC_MDIO	AC8	I/O	OV _{DD}	—
Gigabit Reference Clock				
EC_GTX_CLK125	V11	I	LV _{DD}	—
Three-Speed Ethernet Controller (Gigabit Ethernet 1)				
TSEC1_RXD[7:0]	R5, U1, R3, U2, V3, V1, T3, T2	I	LV _{DD}	—
TSEC1_TXD[7:0]	T10, V7, U10, U5, U4, V6, T5, T8	O	LV _{DD}	5, 9
TSEC1_COL	R4	I	LV _{DD}	—
TSEC1_CRS	V5	I/O	LV _{DD}	20
TSEC1_GTX_CLK	U7	O	LV _{DD}	—
TSEC1_RX_CLK	U3	I	LV _{DD}	—
TSEC1_RX_DV	V2	I	LV _{DD}	—
TSEC1_RX_ER	T1	I	LV _{DD}	—
TSEC1_TX_CLK	T6	I	LV _{DD}	—
TSEC1_TX_EN	U9	O	LV _{DD}	30
TSEC1_TX_ER	T7	O	LV _{DD}	—

Table 71. MPC8548E Pinout Listing (continued)

Signal	Package Pin Number	Pin Type	Power Supply	Notes
				25. These are test signals for factory use only and must be pulled up (100 Ω –1 k Ω) to OV_{DD} for normal machine operation.
				26. Independent supplies derived from board V_{DD} .
				27. Recommend a pull-up resistor (~1 k Ω) be placed on this pin to OV_{DD} .
				29. The following pins must NOT be pulled down during power-on reset: TSEC3_TXD[3], TSEC4_TXD3/TSEC3_TXD7, HRESET_REQ, TRIG_OUT/READY/QUIESCE, MSRCID[2:4], ASLEEP.
				30. This pin requires an external 4.7-k Ω pull-down resistor to prevent PHY from seeing a valid transmit enable before it is actively driven.
				31. This pin is only an output in eTSEC3 FIFO mode when used as Rx flow control.
				32. These pins must be connected to XV_{DD} .
				33. TSEC2_TXD1, TSEC2_TX_ER are multiplexed as <code>cfg_dram_type[0:1]</code> . They must be valid at power-up, even before $\overline{\text{HRESET}}$ assertion.
				34. These pins must be pulled to ground through a 300- Ω ($\pm 10\%$) resistor.
				35. When a PCI block is disabled, either the POR config pin that selects between internal and external arbiter must be pulled down to select external arbiter if there is any other PCI device connected on the PCI bus, or leave the $PCIn_AD$ pins as 'no connect' or terminated through 2–10 k Ω pull-up resistors with the default of internal arbiter if the $PCIn_AD$ pins are not connected to any other PCI device. The PCI block drives the $PCIn_AD$ pins if it is configured to be the PCI arbiter—through POR config pins—irrespective of whether it is disabled via the DEVDISR register or not. It may cause contention if there is any other PCI device connected on the bus.
				36. MDIC0 is grounded through an 18.2- Ω precision 1% resistor and MDIC1 is connected to GV_{DD} through an 18.2- Ω precision 1% resistor. These pins are used for automatic calibration of the DDR IOs.
				38. These pins must be left floating.
				39. If PCI1 or PCI2 is configured as PCI asynchronous mode, a valid clock must be provided on pin $PCI1_CLK$ or $PCI2_CLK$. Otherwise the processor will not boot up.
				40. These pins must be connected to GND.
				101. This pin requires an external 4.7-k Ω resistor to GND.
				102. For Rev. 2.x silicon, $\overline{\text{DMA_DACK}}[0:1]$ must be 0b11 during POR configuration; for rev. 1.x silicon, the pin values during POR configuration are don't care.
				103. If these pins are not used as $GPINn$ (general-purpose input), they must be pulled low (to GND) or high (to LV_{DD}) through 2–10 k Ω resistors.
				104. These must be pulled low to GND through 2–10 k Ω resistors if they are not used.
				105. These must be pulled low or high to LV_{DD} through 2–10 k Ω resistors if they are not used.
				106. For rev. 2.x silicon, $\overline{\text{DMA_DACK}}[0:1]$ must be 0b10 during POR configuration; for rev. 1.x silicon, the pin values during POR configuration are don't care.
				107. For rev. 2.x silicon, $\overline{\text{DMA_DACK}}[0:1]$ must be 0b01 during POR configuration; for rev. 1.x silicon, the pin values during POR configuration are don't care.
				108. For rev. 2.x silicon, $\overline{\text{DMA_DACK}}[0:1]$ must be 0b11 during POR configuration; for rev. 1.x silicon, the pin values during POR configuration are don't care.
				109. This is a test signal for factory use only and must be pulled down (100 Ω – 1 k Ω) to GND for normal machine operation.
				110. These pins must be pulled high to OV_{DD} through 2–10 k Ω resistors.
				111. If these pins are not used as $GPINn$ (general-purpose input), they must be pulled low (to GND) or high (to OV_{DD}) through 2–10 k Ω resistors.
				112. This pin must not be pulled down during POR configuration.
				113. These should be pulled low or high to OV_{DD} through 2–10 k Ω resistors.

Table 72. MPC8547E Pinout Listing (continued)

Signal	Package Pin Number	Pin Type	Power Supply	Notes
TSEC2_TX_ER	R10	O	LV _{DD}	5, 9, 33
Three-Speed Ethernet Controller (Gigabit Ethernet 3)				
TSEC3_TXD[3:0]	V8, W10, Y10, W7	O	TV _{DD}	5, 9, 29
TSEC3_RXD[3:0]	Y1, W3, W5, W4	I	TV _{DD}	—
TSEC3_GTX_CLK	W8	O	TV _{DD}	—
TSEC3_RX_CLK	W2	I	TV _{DD}	—
TSEC3_RX_DV	W1	I	TV _{DD}	—
TSEC3_RX_ER	Y2	I	TV _{DD}	—
TSEC3_TX_CLK	V10	I	TV _{DD}	—
TSEC3_TX_EN	V9	O	TV _{DD}	30
Three-Speed Ethernet Controller (Gigabit Ethernet 4)				
TSEC4_TXD[3:0]/TSEC3_TXD[7:4]	AB8, Y7, AA7, Y8	O	TV _{DD}	1, 5, 9, 29
TSEC4_RXD[3:0]/TSEC3_RXD[7:4]	AA1, Y3, AA2, AA4	I	TV _{DD}	1
TSEC4_GTX_CLK	AA5	O	TV _{DD}	
TSEC4_RX_CLK/TSEC3_COL	Y5	I	TV _{DD}	1
TSEC4_RX_DV/TSEC3_CRS	AA3	I/O	TV _{DD}	1, 31
TSEC4_TX_EN/TSEC3_TX_ER	AB6	O	TV _{DD}	1, 30
DUART				
$\overline{\text{UART_CTS}}[0:1]$	AB3, AC5	I	OV _{DD}	—
$\overline{\text{UART_RTS}}[0:1]$	AC6, AD7	O	OV _{DD}	—
UART_SIN[0:1]	AB5, AC7	I	OV _{DD}	—
UART_SOUT[0:1]	AB7, AD8	O	OV _{DD}	—
I²C Interface				
IIC1_SCL	AG22	I/O	OV _{DD}	4, 27
IIC1_SDA	AG21	I/O	OV _{DD}	4, 27
IIC2_SCL	AG15	I/O	OV _{DD}	4, 27
IIC2_SDA	AG14	I/O	OV _{DD}	4, 27
SerDes				
SD_RX[0:3]	M28, N26, P28, R26	I	XV _{DD}	—
$\overline{\text{SD_RX}}[0:3]$	M27, N25, P27, R25	I	XV _{DD}	—
SD_TX[0:3]	M22, N20, P22, R20	O	XV _{DD}	—
$\overline{\text{SD_TX}}[0:3]$	M23, N21, P23, R21	O	XV _{DD}	—
Reserved	W26, Y28, AA26, AB28	—	—	40
Reserved	W25, Y27, AA25, AB27	—	—	40

Table 72. MPC8547E Pinout Listing (continued)

Signal	Package Pin Number	Pin Type	Power Supply	Notes
Reserved	U20, V22, W20, Y22	—	—	15
Reserved	U21, V23, W21, Y23	—	—	15
SD_PLL_TPD	U28	O	XV _{DD}	24
SD_REF_CLK	T28	I	XV _{DD}	—
$\overline{\text{SD_REF_CLK}}$	T27	I	XV _{DD}	—
Reserved	AC1, AC3	—	—	2
Reserved	M26, V28	—	—	32
Reserved	M25, V27	—	—	34
Reserved	M20, M21, T22, T23	—	—	38
General-Purpose Output				
GPOUT[24:31]	K26, K25, H27, G28, H25, J26, K24, K23	O	BV _{DD}	—
System Control				
$\overline{\text{HRESET}}$	AG17	I	OV _{DD}	—
$\overline{\text{HRESET_REQ}}$	AG16	O	OV _{DD}	29
$\overline{\text{SRESET}}$	AG20	I	OV _{DD}	—
$\overline{\text{CKSTP_IN}}$	AA9	I	OV _{DD}	—
$\overline{\text{CKSTP_OUT}}$	AA8	O	OV _{DD}	2, 4
Debug				
TRIG_IN	AB2	I	OV _{DD}	—
TRIG_OUT/READY/QUIESCE	AB1	O	OV _{DD}	6, 9, 19, 29
MSRCID[0:1]	AE4, AG2	O	OV _{DD}	5, 6, 9
MSRCID[2:4]	AF3, AF1, AF2	O	OV _{DD}	6, 19, 29
MDVAL	AE5	O	OV _{DD}	6
CLK_OUT	AE21	O	OV _{DD}	11
Clock				
RTC	AF16	I	OV _{DD}	—
SYSCLK	AH17	I	OV _{DD}	—
JTAG				
TCK	AG28	I	OV _{DD}	—
TDI	AH28	I	OV _{DD}	12
TDO	AF28	O	OV _{DD}	—
TMS	AH27	I	OV _{DD}	12
$\overline{\text{TRST}}$	AH23	I	OV _{DD}	12

Table 72. MPC8547E Pinout Listing (continued)

Signal	Package Pin Number	Pin Type	Power Supply	Notes
SD_PLL_TPA	U26	O	—	24

Note: All note references in this table use the same numbers as those for Table 71. See Table 71 for the meanings of these notes.

Table 73 provides the pin-out listing for the MPC8545E 783 FC-PBGA package.

NOTE

All note references in the following table use the same numbers as those for Table 71. See Table 71 for the meanings of these notes.

Table 73. MPC8545E Pinout Listing

Signal	Package Pin Number	Pin Type	Power Supply	Notes
PCI1 and PCI2 (One 64-Bit or Two 32-Bit)				
PCI1_AD[63:32]/PCI2_AD[31:0]	AB14, AC15, AA15, Y16, W16, AB16, AC16, AA16, AE17, AA18, W18, AC17, AD16, AE16, Y17, AC18, AB18, AA19, AB19, AB21, AA20, AC20, AB20, AB22, AC22, AD21, AB23, AF23, AD23, AE23, AC23, AC24	I/O	OV _{DD}	17
PCI1_AD[31:0]	AH6, AE7, AF7, AG7, AH7, AF8, AH8, AE9, AH9, AC10, AB10, AD10, AG10, AA10, AH10, AA11, AB12, AE12, AG12, AH12, AB13, AA12, AC13, AE13, Y14, W13, AG13, V14, AH13, AC14, Y15, AB15	I/O	OV _{DD}	17
PCI1_C_BE[7:4]/PCI2_C_BE[3:0]	AF15, AD14, AE15, AD15	I/O	OV _{DD}	17
PCI1_C_BE[3:0]	AF9, AD11, Y12, Y13	I/O	OV _{DD}	17
PCI1_PAR64/PCI2_PAR	W15	I/O	OV _{DD}	—
PCI1_GNT[4:1]	AG6, AE6, AF5, AH5	O	OV _{DD}	5, 9, 35
PCI1_GNT0	AG5	I/O	OV _{DD}	—
PCI1_IRDY	AF11	I/O	OV _{DD}	2
PCI1_PAR	AD12	I/O	OV _{DD}	—
PCI1_PERR	AC12	I/O	OV _{DD}	2
PCI1_SERR	V13	I/O	OV _{DD}	2, 4
PCI1_STOP	W12	I/O	OV _{DD}	2
PCI1_TRDY	AG11	I/O	OV _{DD}	2
PCI1_REQ[4:1]	AH2, AG4, AG3, AH4	I	OV _{DD}	—
PCI1_REQ0	AH3	I/O	OV _{DD}	—
PCI1_CLK	AH26	I	OV _{DD}	39
PCI1_DEVSEL	AH11	I/O	OV _{DD}	2

Table 74. MPC8543E Pinout Listing (continued)

Signal	Package Pin Number	Pin Type	Power Supply	Notes
JTAG				
TCK	AG28	I	OV _{DD}	—
TDI	AH28	I	OV _{DD}	12
TDO	AF28	O	OV _{DD}	—
TMS	AH27	I	OV _{DD}	12
$\overline{\text{TRST}}$	AH23	I	OV _{DD}	12
DFT				
L1_TSTCLK	AC25	I	OV _{DD}	25
L2_TSTCLK	AE22	I	OV _{DD}	25
$\overline{\text{LSSD_MODE}}$	AH20	I	OV _{DD}	25
TEST_SEL	AH14	I	OV _{DD}	109
Thermal Management				
THERM0	AG1	—	—	14
THERM1	AH1	—	—	14
Power Management				
ASLEEP	AH18	O	OV _{DD}	9, 19, 29
Power and Ground Signals				
GND	A11, B7, B24, C1, C3, C5, C12, C15, C26, D8, D11, D16, D20, D22, E1, E5, E9, E12, E15, E17, F4, F26, G12, G15, G18, G21, G24, H2, H6, H8, H28, J4, J12, J15, J17, J27, K7, K9, K11, K27, L3, L5, L12, L16, N11, N13, N15, N17, N19, P4, P9, P12, P14, P16, P18, R11, R13, R15, R17, R19, T4, T12, T14, T16, T18, U8, U11, U13, U15, U17, U19, V4, V12, V18, W6, W19, Y4, Y9, Y11, Y19, AA6, AA14, AA17, AA22, AA23, AB4, AC2, AC11, AC19, AC26, AD5, AD9, AD22, AE3, AE14, AF6, AF10, AF13, AG8, AG27, K28, L24, L26, N24, N27, P25, R28, T24, T26, U24, V25, W28, Y24, Y26, AA24, AA27, AB25, AC28, L21, L23, N22, P20, R23, T21, U22, V20, W23, Y21, U27	—	—	—
OV _{DD}	V16, W11, W14, Y18, AA13, AA21, AB11, AB17, AB24, AC4, AC9, AC21, AD6, AD13, AD17, AD19, AE10, AE8, AE24, AF4, AF12, AF22, AF27, AG26	Power for PCI and other standards (3.3 V)	OV _{DD}	—
LV _{DD}	N8, R7, T9, U6	Power for TSEC1 and TSEC2 (2.5 V, 3.3 V)	LV _{DD}	—

21 Thermal

This section describes the thermal specifications of the device.

21.1 Thermal for Version 2.0 Silicon HiCTE FC-CBGA with Full Lid

This section describes the thermal specifications for the HiCTE FC-CBGA package for revision 2.0 silicon.

This table shows the package thermal characteristics.

Table 84. Package Thermal Characteristics for HiCTE FC-CBGA

Characteristic	JEDEC Board	Symbol	Value	Unit	Notes
Die junction-to-ambient (natural convection)	Single-layer board (1s)	$R_{\theta JA}$	17	°C/W	1, 2
Die junction-to-ambient (natural convection)	Four-layer board (2s2p)	$R_{\theta JA}$	12	°C/W	1, 2
Die junction-to-ambient (200 ft/min)	Single-layer board (1s)	$R_{\theta JA}$	11	°C/W	1, 2
Die junction-to-ambient (200 ft/min)	Four-layer board (2s2p)	$R_{\theta JA}$	8	°C/W	1, 2
Die junction-to-board	N/A	$R_{\theta JB}$	3	°C/W	3
Die junction-to-case	N/A	$R_{\theta JC}$	0.8	°C/W	4

Notes:

1. Junction temperature is a function of die size, on-chip power dissipation, package thermal resistance, mounting site (board) temperature, ambient temperature, airflow, power dissipation of other components on the board, and board thermal resistance.
2. Per JEDEC JESD51-6 with the board (JESD51-7) horizontal.
3. Thermal resistance between the die and the printed-circuit board per JEDEC JESD51-8. Board temperature is measured on the top surface of the board near the package.
4. Thermal resistance between the die and the case top surface as measured by the cold plate method (MIL SPEC-883 Method 1012.1). The cold plate temperature is used for the case temperature, measured value includes the thermal resistance of the interface layer.

21.2 Thermal for Version 2.1.1, 2.1.2, and 2.1.3 Silicon FC-PBGA with Full Lid and Version 3.1.x Silicon with Stamped Lid

This section describes the thermal specifications for the FC-PBGA package for revision 2.1.1, 2.1.2, and 3.0 silicon.

This table shows the package thermal characteristics.

Table 85. Package Thermal Characteristics for FC-PBGA

Characteristic	JEDEC Board	Symbol	Value	Unit	Notes
Die junction-to-ambient (natural convection)	Single-layer board (1s)	$R_{\theta JA}$	18	°C/W	1, 2
Die junction-to-ambient (natural convection)	Four-layer board (2s2p)	$R_{\theta JA}$	13	°C/W	1, 2
Die junction-to-ambient (200 ft/min)	Single-layer board (1s)	$R_{\theta JA}$	13	°C/W	1, 2
Die junction-to-ambient (200 ft/min)	Four-layer board (2s2p)	$R_{\theta JA}$	9	°C/W	1, 2

level must always be equivalent to V_{DD} , and preferably these voltages are derived directly from V_{DD} through a low frequency filter scheme such as the following.

There are a number of ways to reliably provide power to the PLLs, but the recommended solution is to provide independent filter circuits per PLL power supply as illustrated in [Figure 57](#), one to each of the AV_{DD} pins. By providing independent filters to each PLL the opportunity to cause noise injection from one PLL to the other is reduced.

This circuit is intended to filter noise in the PLLs resonant frequency range from a 500 kHz to 10 MHz range. It must be built with surface mount capacitors with minimum Effective Series Inductance (ESL). Consistent with the recommendations of Dr. Howard Johnson in *High Speed Digital Design: A Handbook of Black Magic* (Prentice Hall, 1993), multiple small capacitors of equal value are recommended over a single large value capacitor.

Each circuit must be placed as close as possible to the specific AV_{DD} pin being supplied to minimize noise coupled from nearby circuits. It must be routed directly from the capacitors to the AV_{DD} pin, which is on the periphery of the footprint, without the inductance of vias.

[Figure 57](#) through [Figure 59](#) shows the PLL power supply filter circuits.

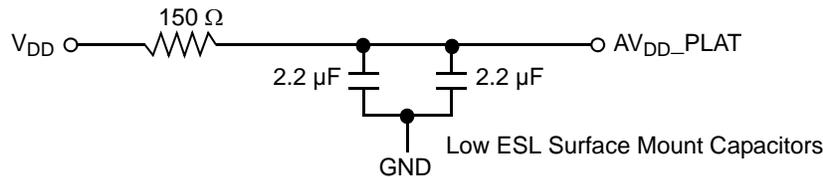


Figure 57. PLL Power Supply Filter Circuit with PLAT Pins

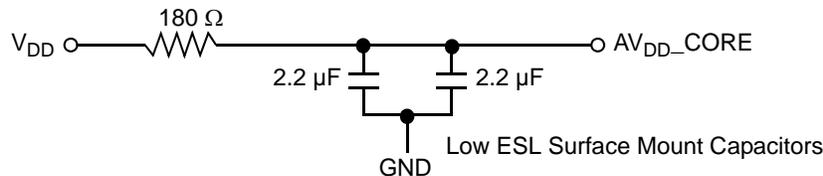


Figure 58. PLL Power Supply Filter Circuit with CORE Pins

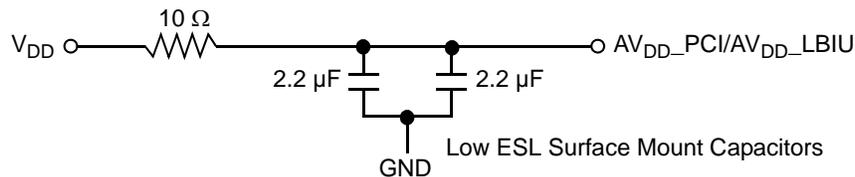


Figure 59. PLL Power Supply Filter Circuit with PCI/LBIU Pins

The AV_{DD_SRDS} signal provides power for the analog portions of the SerDes PLL. To ensure stability of the internal clock, the power supplied to the PLL is filtered using a circuit similar to the one shown in following figure. For maximum effectiveness, the filter circuit is placed as closely as possible to the AV_{DD_SRDS} ball to ensure it filters out as much noise as possible. The ground connection must be near the AV_{DD_SRDS} ball. The 0.003- μF capacitor is closest to the ball, followed by the two 2.2 μF capacitors, and finally the 1 Ω resistor to the board supply plane. The capacitors are connected from AV_{DD_SRDS} to

Table 87. Part Numbering Nomenclature (continued)

MPC	nnnnn	t	pp	ff	c	r
Product Code	Part Identifier	Temperature	Package ^{1, 2, 3}	Processor Frequency ⁴	Core Frequency	Silicon Version
MPC	8545E	Blank = 0 to 105°C C = -40° to 105°C	HX = CBGA VU = Pb-free CBGA PX = PBGA VT = Pb-free PBGA	AT = 1200 AQ = 1000 AN = 800	G = 400	Blank = Ver. 2.0 (SVR = 0x80390220) A = Ver. 2.1.1 B = Ver. 2.1.2 D = Ver. 3.1.x (SVR = 0x80390231)
	8545					Blank = Ver. 2.0 (SVR = 0x80310220) A = Ver. 2.1.1 B = Ver. 2.1.2 D = Ver. 3.1.x (SVR = 0x80310231)
	8543E			AQ = 1000 AN = 800		Blank = Ver. 2.0 (SVR = 0x803A0020) A = Ver. 2.1.1 B = Ver. 2.1.2 D = Ver. 3.1.x (SVR = 0x803A0031)
	8543			Blank = Ver. 2.0 (SVR = 0x80320020) A = Ver. 2.1.1 B = Ver. 2.1.2 D = Ver. 3.1.x (SVR = 0x80320031)		

Notes:

- See Section 19, "Package Description," for more information on available package types.
- The HiCTE FC-CBGA package is available on only Version 2.0 of the device.
- The FC-PBGA package is available on only Version 2.1.1, 2.1.2, and 2.1.3 of the device.
- Processor core frequencies supported by parts addressed by this specification only. Not all parts described in this specification support all core frequencies. Additionally, parts addressed by part number specifications may support other maximum core frequencies.
- This speed available only for silicon Version 2.1.1, 2.1.2, and 2.1.3.

24 Document Revision History

The following table provides a revision history for this hardware specification.

Table 88. Document Revision History

Rev. Number	Date	Substantive Change(s)
9	02/2012	<ul style="list-style-type: none"> Updated Section 21.2, "Thermal for Version 2.1.1, 2.1.2, and 2.1.3 Silicon FC-PBGA with Full Lid and Version 3.1.x Silicon with Stamped Lid," with version 3.0 silicon information. Added Figure 56, "Mechanical Dimensions and Bottom Surface Nomenclature of the FC-PBGA with Stamped Lid." Updated Table 87, "Part Numbering Nomenclature," with version 3.0 silicon information. Removed Note from Section 5.1, "Power-On Ramp Rate". Changed the Table 10 title to "Power Supply Ramp Rate". Removed table 11. Updated the title of Section 21.2, "Thermal for Version 2.1.1, 2.1.2, and 2.1.3 Silicon FC-PBGA with Full Lid and Version 3.1.x Silicon with Stamped Lid" to include Thermal Version 2.1.3 and Version 3.1.x Silicon. Corrected the leaded Solder Ball composition in Table 70, "Package Parameters" Updated Table 87, "Part Numbering Nomenclature," with Version 3.1.x silicon information. Updated the Min and Max value of TDO in the valid times row of Table 44, "JTAG AC Timing Specifications (Independent of SYSCLK)"¹ from 4 and 25 to 2 and 10 respectively .
8	04/2011	<ul style="list-style-type: none"> Added Section 14.1, "GPOUT/GPIN Electrical Characteristics." Updated Table 71, "MPC8548E Pinout Listing," Table 72, "MPC8547E Pinout Listing," Table 73, "MPC8545E Pinout Listing," and Table 74, "MPC8543E Pinout Listing," to reflect that the TDO signal is not driven during HRSET* assertion. Updated Table 87, "Part Numbering Nomenclature" with Ver. 2.1.3 silicon information.
7	09/2010	<ul style="list-style-type: none"> In Table 37, "MII Management AC Timing Specifications," modified the fifth row from "MDC to MDIO delay tMDKHDX (16 × tptb_clk × 8) – 3 — (16 × tptb_clk × 8) + 3" to "MDC to MDIO delay tMDKHDX (16 × tCCB × 8) – 3 — (16 × tCCB × 8) + 3." Updated Figure 55, "Mechanical Dimensions and Bottom Surface Nomenclature of the HiCTE FC-CBGA and FC-PBGA with Full Lid and figure notes.
6	12/2009	<ul style="list-style-type: none"> In Section 5.1, "Power-On Ramp Rate" added explanation that Power-On Ramp Rate is required to avoid falsely triggering ESD circuitry. In Table 13 changed required ramp rate from 545 V/s for MVREF and VDD/XVDD/SVDD to 3500 V/s for MVREF and 4000 V/s for VDD. In Table 13 deleted ramp rate requirement for XVDD/SVDD. In Table 13 footnote 1 changed voltage range of concern from 0–400 mV to 20–500mV. In Table 13 added footnote 2 explaining that VDD voltage ramp rate is intended to control ramp rate of AVDD pins.
5	10/2009	<ul style="list-style-type: none"> In Table 27, "GMII Receive AC Timing Specifications," changed duty cycle specification from 40/60 to 35/75 for RX_CLK duty cycle. Updated tMDKHDX in Table 37, "MII Management AC Timing Specifications." Added a reference to Revision 2.1.2. Updated Table 55, "MII Management AC Timing Specifications." Added Section 5.1, "Power-On Ramp Rate."